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The search of 28Si doubly charged negative ion by Accelerator Mass Spectrometry

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Here we search the 28Si doubly charged negative ion (28Si DCNI) with Accelerator Mass Spectrometry (AMS). Five kinds of silicon including samples made of Si, Si+Fe, Si3N4, SiO2+Fe, and Si3N4+Fe were prepared to find 28Si DCNI. These samples were loaded into an AMS, which was a tandem type machine with a negative ion source by cesium sputtering (SNICS). The ions produced from these samples went through the AMS and were measured in ΔE-Eresdual of an ionization detector. The existence of the 28Si DCNI (28Si2-) was originally believed to be in the spectrum of ΔE-Eresdual of the AMS.

Student Submission

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